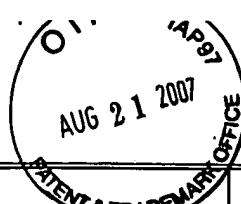


SHEET 1 OF 1

<p align="center">LIST OF ART CITED BY APPLICANT (PTO-1449)</p>			ATTY. DOCKET NO. P-0601	APPLN. SERIAL NO. 10/733,515		
			APPLICANT(S) Choong-Jae LEE			
			FILING DATE December 12, 2003	GROUP 2615		
U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
/PD/	6,064,453	05/16/2000	Inubushi et al.	349	58	08/06/1998
U.S. PATENT APPLICATION PUBLICATIONS						
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
/PD/	2002/0128053	09/12/2002	Kwang Shin JUNG	455	575	03/07/2002
U.S. PATENT APPLICATIONS						
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
						Yes
						No
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)						
EXAMINER	DATE CONSIDERED					
/Phylesha Dabney/				02/20/2008		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.
 \\Flk4\\Documents\\2000\\2000-702\\143219.doc



SHEET 1 OF 1

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(PTO-1449)**

ATTY. DOCKET NO. P-0601 APPLN. SERIAL NO. 10/733,515

APPLICANT(S) Choong-Jae LEE

FILING DATE December 12, 2003 GROUP 2615

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
/PD/	6,229,994	05/08/2001	Pavet	455	90	02/04/1999

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
/PD/	CN 1233126	10/27/1999	China (English Abstract & Full Chinese Text)			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

Chinese Office Action dated June 1, 2007 (English and Chinese)

EXAMINER	DATE CONSIDERED
/Phylesha Dabney/	02/20/2008

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JUN 05 2007

SHEET 1 OF 1

**LIST OF ART CITED BY APPLICANT
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ATTY. DOCKET NO.
P-0601APPLN. SERIAL NO.
10/733,515

APPLICANT(S)

Choong-Jae LEE

FILING DATE

December 12, 2003

GROUP

2615

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
/PD/	KR 0038013/2002	05/2002	Korea (English Abstract & Full Korean Text)				

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

EXAMINER

/Phylesha Dabney/

DATE CONSIDERED

02/20/2008

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